Heusler Alloy Films for **Spintronic Devices**



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Where is York ?





Requirements for device implementations for Heusler alloys :



* A. Hirohata et al., Heusler Alloys (Springer, in press).



Possible Solutions

Smoothing the interfaces :

- Optimisation of the non-magnetic spacer $\rightarrow Aq$
- Atomically sharp interface achieved

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ightarrow GMR ratio : ~ 15 %
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Elimination of minor domains :

Maximisation of activation volume

 \rightarrow smallest volume that reverses in a single step



Minimisation of intermixing / deformation :

Low-temperature annealing for Heusler alloy films

 \rightarrow *in situ* TEM observation



* V. K. Lazarov *et al.*, *Appl. Phys. Lett.* 98, 242508 (2011).

Activation Volumes in Heusler Alloy Films



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Engineering and Physical Sciences Research Council

Co₂FeSi Heusler-Alloy Epitaxial Film Growth

- Sample Structure:

MgO [100]//MgO (10nm) / Co₂FeSi (2nm) / Ru (2nm)

- MgO substrate annealed at 800°C before deposition of a 10 nm MgO buffer layer and annealing again at 400°C.

- Co_2FeSi deposited by UHV magnetron sputtering with base pressure of better than $3x10^{-7}$ Pa at a rate of 0.03 nm/s

- Post deposition AFM measurements of samples found R_a to be 4.7 nm

- *Ex-situ* post deposition annealing at 400°C, 500°C and 600°C to cause recystallisation into B2 and *L*2₁ phases.





- X-ray diffraction (XRD) spectra were taken for as-deposited and post annealed films.

- 2θ - ω (out-of-plane) and 2θ - $\varphi \chi$ (in plane) scans have been taken.
- This allows for structural characterisation and identification of order phases.
- Increasing intensity (200) and (400) peaks are characteristic of B2 and $L2_1$ ordering.
- Increased intensity (111) peaks in the 2θ - $\varphi\chi$ show increased $L2_1$ ordering with increasing anneal temperature.





- HAADF STEM imaging with elemental contrast can be used for structural analysis of Heusler alloy films

- Using digital diffractograms and measurements of inter-atomic spacing, the in-plane and out-of-plane lattice constants have been found.

- From the [111] spots the in-plane lattice constant was found to be (5.74 \pm 0.05) Å compared with the bulk value of 5.64 Å

- From the [200] spots the out-of-plane lattice constant was found to be slightly reduced at (5.44 \pm 0.05) Å

- The volume of the unit cell was found to lie within error of the bulk value.



Co₂FeSi Heusler-Alloy Film Growth

- The lattice constant for Co_2FeSi is 5.64 Å and for MgO is 4.17 Å, this is a mismatch of 35%.

- To compensate for this mismatch the Co_2FeSi unit cell is found to rotate by 45° to align the Co_2FeSi [110] planes with the MgO [100].

- This rotation allows the Co_2FeSi to span two MgO unit cells and reduces the mismatch to 4.5 %.





False colour diffraction pattern showing Co₂FeSi [110] and MgO [100] reflections. <u>X</u>

- Magnetic time dependence measurements have been taken over the switching region.

- These measurements are used to find a value for the magnetic viscosity $S_1(H)$ of each sample.

$$\frac{-dM(H)}{d\ln t} = S_0 + S_1(H) \ln t + (S_2(H) \ln t)^2 + \dots$$

- DC demagnetised (DCD) remanence curves have also been taken for each sample.

- For a DCD curve the sample is saturated, then the remanent magnetisation (M_r) is measured at increasing values of negative field.



<u>____</u>

- The fluctuation field (H_f) is an imaginary field representing the effect of thermal energy.^{*}

- The differential of the DCD curve gives₃ the irreversible susceptibility (χ_{irr}) . $\chi_{irr}(H) = \frac{d(DCD(H))}{dH}$ ²

- This can be combined with the value for $S_1(H)$ to give the fluctuation field (H_f) .

$$H_f = \frac{S_1(H)}{\chi_{irr}(H)}$$



* L. Néel, Ann. Geophys. 5, 99 (1949).

Estimated Activation Volumes

- $H_{\rm f}$ then gives rise to the concept of the activation volume ($V_{\rm act}$) : *

$$V_{act} = \frac{k_{B}T}{M_{s}H_{f}}$$

- $V_{\rm act}$ is defined as the smallest volume that reverses in a single step.



- $V_{\rm act}$ is a relative measure because the value of $M_{\rm s}$ is unsure.

Annealing Condition	M _s (±0.1 emu/cc x10 ⁴)	V _{act} (±0.5x10 ⁻¹⁷ cm ³)	D _{act} (±0.5 nm)	Н _с (±0.1 Ое)
As – deposited	4.4	4.0	5.0	2.9
400°C	5.2	1.6	3.2	1.7
500°C	4.5	4.5	5.3	4.5
600°C	4.8	4.6	5.4	7.2

* E. P. Wohlfarth, J. Phys. F: Met. Phys. 14, 155 (1984).

Activation Volume in Epitaxial Co₂FeSi

Activation volume was estimated to be
 4.0 nm.

- A lattice mismatch of 4.5 % to be compensated between MgO and Co_2FeSi .

- This compensation layer (periodic contrast) can be seen in the contrast change in the TEM image due to an increase in lattice spacing through this layer.

- This contrast change is due to compensation through the Co₂FeSi missing entire MgO planes to improve the epitaxy.





* A. Hirohata et al., Appl. Phys. A 111, 423 (2013).

Pinned / Unpinned Domain Wall





~ 25 pinning sites (epitaxial)

* J. Sagar et al., Appl. Phys. Lett. 101, 102410 (2013).

Heusler-Alloy Film Growth

- Sputter film deposition : *
- Controlled plasma HiTUS sputtering system
- Optimised target composition (e.g., Co_{1.748}Mn_{1.118}Si_{1.134})
- Base pressure : < 3.0 \times 10 $^{-5}$ Pa
- MgO (001) substrate cleaning : acetone bath for 10 min. + *in situ* heat treatment at 573 K for 20 min.

• Plasma :

RF field at 3.0 \times 10 $^{-1}$ Pa Ar pressure

DC bias steering from -250 to -990 V to change the grain size

• Annealing at 760 K for 3 h (1st anneal)

followed by further annealing at 760 K for another 3 h (2nd anneal) additional annealing at 760 K for 3 h (3rd anneal)



Magnetic / structural measurements :

- Princeton AGFM Model 2900
- ADE Model 10 VSM
- JEOL JEM-2011 TEM
- JEOL JEM-2200FS HR-(S)TEM

* A. Hirohata et al., Appl. Phys. Lett. 95, 252506 (2009).



Activation Volume in Polycrystalline Co₂FeSi

- The activation volume has been shown to be bias voltage independent (~ 40 nm), but varies with annealing time.

- The physical grain volume is shown to increase with bias voltage and vary with annealing time.
- For films deposited at higher bias voltages the activation volume was 40% of the physical volume the particles are therefore multi-domain.
- Polycrystalline films can offer a "pinningsite-free" nano-pillar.



* J. Sagar et al., IEEE Trans. Magn. 47, 2440 (2011).



Possible Solutions

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ightarrow GMR ratio : ~ 15 %



- Elimination of minor domains :
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Minimisation of intermixing / deformation :

- Low-temperature annealing for Heusler alloy films
 - \rightarrow in situ TEM observation



* V. K. Lazarov *et al.*, *Appl. Phys. Lett.* 98, 242508 (2011).

For example, Ni₂Mn(Ga,AI) : *



* H. Ishikawa *et al.*, *Acta Mater.* **56**, 4789 (2008); ** A. Hirohata *et al.*, *Heusler Alloys* (Springer, in press).

Deformation of Polycrystalline Co₂FeSi

- After annealing at 500 °C for 6 h, a 20 nm thick Co_2FeSi film crystallises 3-dimensionally.

- This forms ~ 230 nm high grain.
- This induces the discontinuity of the $\rm Co_2 FeSi$ films.

- Lower-temperature annealing with shorter period is necessary to minimise the deformation.



Low-Temperature Crystallisation of Heusler Alloy Films



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EPSRC *EP/H026126/1 EP/M02458X/1*

Engineering and Physical Sciences Research Council

In situ TEM observation :



JEOL JEM-2200FS :

- Double Cs correction
- Gas introduction to sample space
- Gatan heating sample stage (< 700°C)

Heusler-alloy films :

- 20 nm Co₂FeSi / 2 nm Ru
- Grown on SiN TEM grids
- Continuous movie (Camtasia studio)
- Detailed HRTEM / diffractograms



K.



Bright Field TEM (235°C for 3 hours)

Electron diffraction pattern (235°C for 3 hours) Initial grain nucleation :

X



<111>





* J. Sagar et al., Appl. Phys. Lett. 105, 032401 (2014).

Structural Analysis of Individual Grains

Grain evolution :

500 nm



20

120 mins



Grain crystalline orientation :

X



* A. Hirohata et al., British Patent, GB1402399.8.



Structural analysis on Co₂FeSi grains using HRTEM :

- The analysis was performed on the 6hour annealed sample with the maximum grain size.

 The grains were analysed using SAED patterns and digital diffractograms of HRTEM images.

Each of the grains analysed showed a very well ordered structure, lying predominantly along the [112] orientation, possibly in the L2₁ phase.





* L. R. Fleet et al., J. Phys. D: Appl. Phys. 45, 032001(FTC) (2012).

Layer-by-Layer Crystallisation

Cross-sectional analysis on Co₂FeSi films using HRTEM :

- Single-nanocrystalline grains with the $L2_1$ phase were observed along the [112] axis.

- Image simulations were produced using the multislice method in the electron microscopy software JEMS. *

- The grains were assumed to be in the $L2_1$ phase, orientated along the [112] zone axis.

- The simulations were found to match with the experimental HRTEM images.

- This implies the grains are in the $L2_1$ phase and crystallised in a layer-by-layer growth mode.





* P. Stadelmann, http://cimewww.epfl.ch/people/Stadelmann/jemsWebSite/jems.html.

 $V_{\rm B}$ = 990 V after 9 h annealing

- □ Small grains of ~ 10 nm begin to form at around 230°C. These grains continue to grow up to ~ 200 nm in size when held at 230°C for 3 hours.
- **\Box** The lattice constant was estimated to be 0.565 nm (expected for $L2_1$ ordering).
- Further annealing does not appear to cause any significant change in the films but does effect the structure of the grains with striping occurring after annealing over 500°C.
- □ Magnetic moments gave 80 % of the theoretical maximum value.
 - \rightarrow Evidence for the presence of the L2₁ phase.
- HRTEM images and SAED patterns show ordered grains lying in the (110) orientation.
 - \rightarrow Grains crystallising in a layer-by-layer mode.

Heusler Alloy Replacement for Iridium



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The Scarcest Material





* http://www.atheistfrontier.com/people/dmitri-mendeleyev/periodic-table-of-the-elements-for-kids.jpg





<u>Aim</u>

IrMn alloy used in GMR / TMR junctions

 \rightarrow Antiferromagnetic Heusler alloys with common elements

Objectives

Exchange bias : $H_{ex} > 1$ kOe ($J_{K} > 1$ erg/cm²)

Blocking temperature : $T_{\rm B}$ > 300 K

Distribution of the blocking temperature : $\sigma_{\text{TB}} < 0.3$



- Antiferromagnetic Heusler alloys have been successfully grown.
- □ Exchange bias has been observed at low temperature.
- Further optimisation on the crystallisation is required to achieve antiferromagnetism at room temperature.
 - \rightarrow Such a layer is ideal for next-generation junctions.

Polycrystalline Heusler-alloy films can

form a junction to be reversed in a single step.

 \bullet crystallise at below 300 $^\circ\,$ C compatible with the CMOS technology.

• exhibit exchange bias against a ferromagnetic layer.

Roadmap on Heusler Alloys



* A. Hirohata et al., IEEE Trans. Magn. 51, 07160747 (2015).



Other Group Activities





Special thanks to ...



& York colleagues



13th Joint MMM-Intermag Conference January 11-15, 2016 San Diego, California

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